

| Form 100-249 | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. M122-1196 | | SERIAL NO. 09/388,063 | | |
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| <div style="text-align: center;"> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) </div> | | | | APPLICANT Vishnu K. Agarwal | | | | |
| | | | | FILING DATE August 30, 1999 | | GROUP 2815 | | |
| U.S. PATENT DOCUMENTS | | | | | | | | |
| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate | |
| [Signature] | AA | 6,037,205 | 3/14/00 | Huh et al | | | | |
| | AB | 5,470,398 | 11/28/95 | Shibuya, et al. | | | | |
| | AC | 5,254,505 | 10/19/93 | Kamiyama | | | | |
| | AD | 6,156,638 | 12/05/00 | Agarwal et al. | | | | |
| | AE | 6,165,834 | 12/26/00 | Agarwal et al. | | | | |
| | AF | | | | | | | |
| | AG | | | | | | | |
| | AH | | | | | | | |
| | AI | | | | | | | |
| | AJ | | | | | | | |
| | AK | | | | | | | |
| | AL | | | | | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | | |
| | | Document Number | Date | Country | Class | Subclass | Translation | |
| | | | | | | | Yes | No |
| [Signature] | AM | WO 98/39497 | 09/11/98 | Japan, Simpson, et al. | | | | |
| | AN | 0 474 140 A1 | 08/30/91 | Europe, Kamiyama | | | | |
| | AO | WO 99/64645 | 12/16/99 | WIPO, Narwankar, et al. | | | | |
| | AP | | | | | | | |
| | AQ | | | | | | | |
| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | | |
| [Signature] | AR | JP | Kim, et al.: "Structural and Electrical Properties..." Applied Physics Letters, US, American Institute of Physics Vol. 65, No. 15, 10/10/94, Pgs. 1955 - 1957 | | | | | |
| | AS | JP | Arai T., et al.: "Preparation of SrTiO ₃ Films on 8-Inch Wafers..." Jap. Journal of Applied Physics. Vol. 35, No. 9B, Part 01, 09/01/96, Pgs. 4875-4879. | | | | | |
| EXAMINER [Signature] | | | | DATE CONSIDERED 11/14/01 | | | | |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | | |